

結晶系SiGeナローギャップ材料太陽電池の開発

Narrow-gap crystalline SiGe thin-film solar cells with heterojunctions

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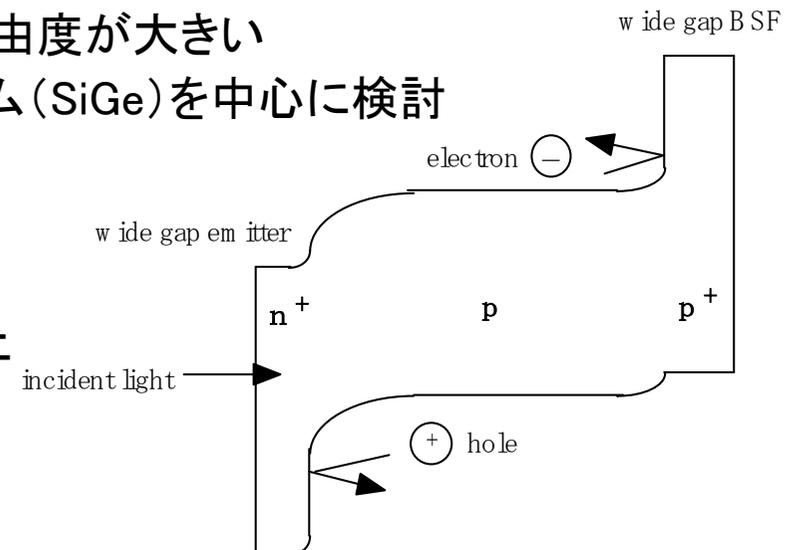
背景と目的

精密制御結晶系へテロ接合太陽電池

- ・単結晶Ge太陽電池では従来ほとんど検討例がない
- ・分子線ビームエピタキシー(MBE) → 組成、歪制御によるへテロ接合の形成、バンドプロファイルの高精度変調 → 設計自由度が大きい
- ・ナローギャップ材料としてはシリコンゲルマニウム(SiGe)を中心に検討
バンドギャップ: 0.75~0.9eV

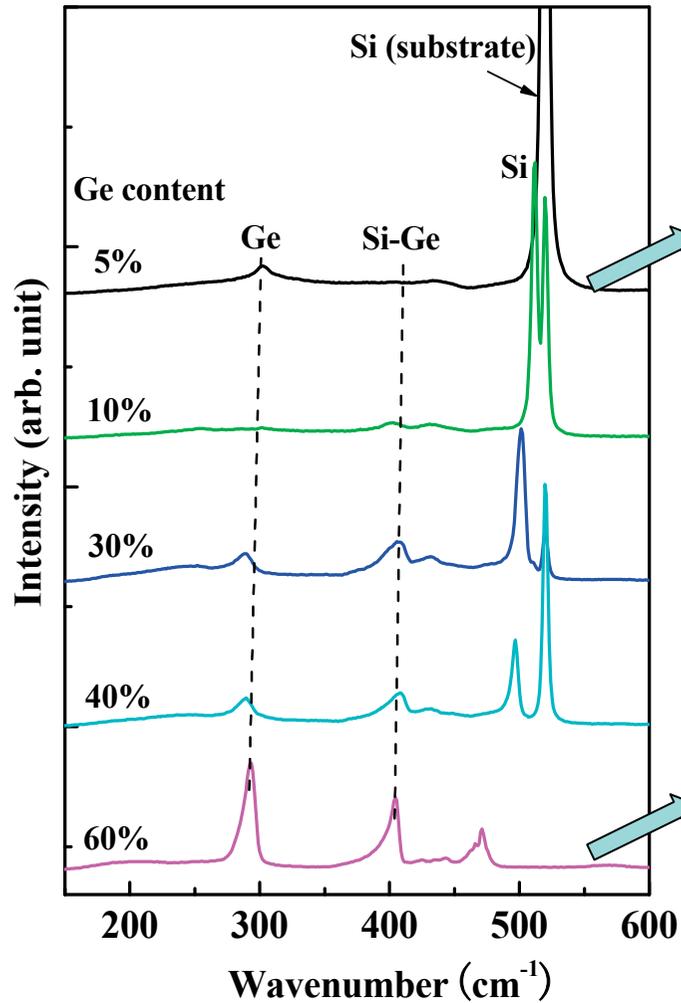
期待される効果:

- ・接合の組み込み電圧の向上 → 開放電圧向上
- ・界面再結合速度の低減 → 開放電圧向上
- ・温度特性の改善
- ・新しい光起電力過程の可能性検討



Epitaxial growth of SiGe on Si substrate by MBE

Raman spectra of SiGe on Si

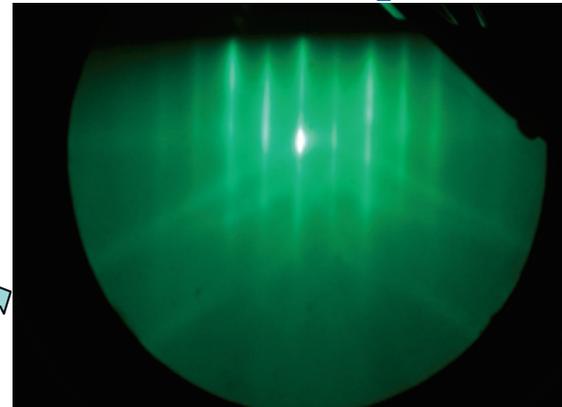


RHEED patterns

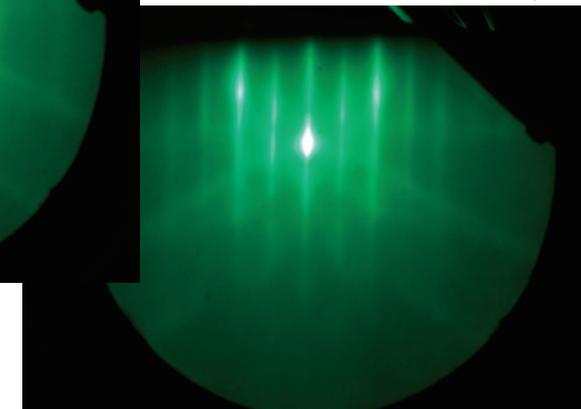
T_{sub}=500C

Si_{0.95}Ge_{0.05}

Thick layer

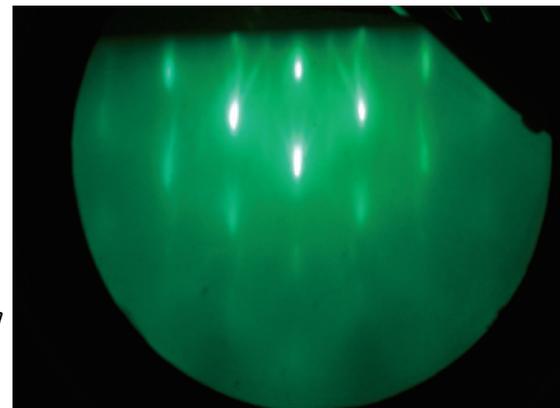


Initial growth
(Interface)

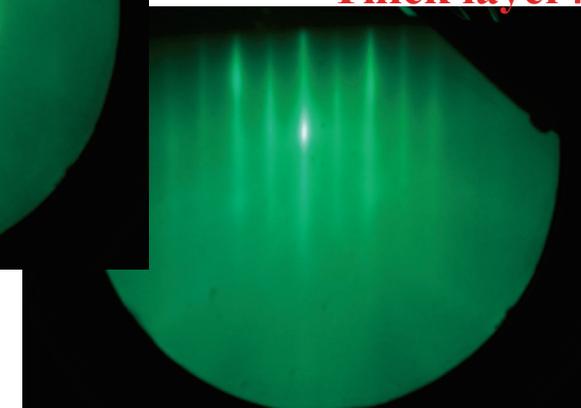


Si_{0.4}Ge_{0.6}

Thick layer: 5μm

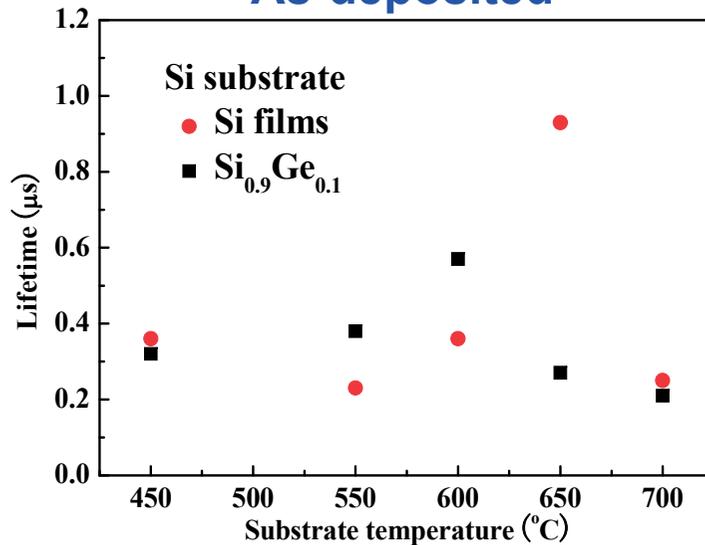


Initial growth
(Interface)

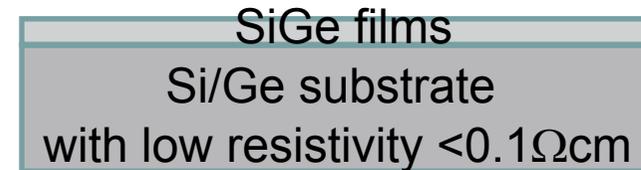


Characterization of carrier lifetime for SiGe films

As-deposited

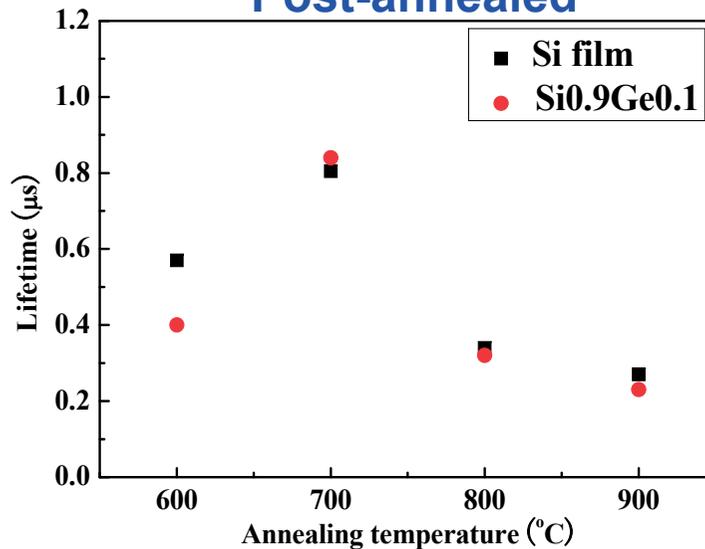


◆ Sample preparation

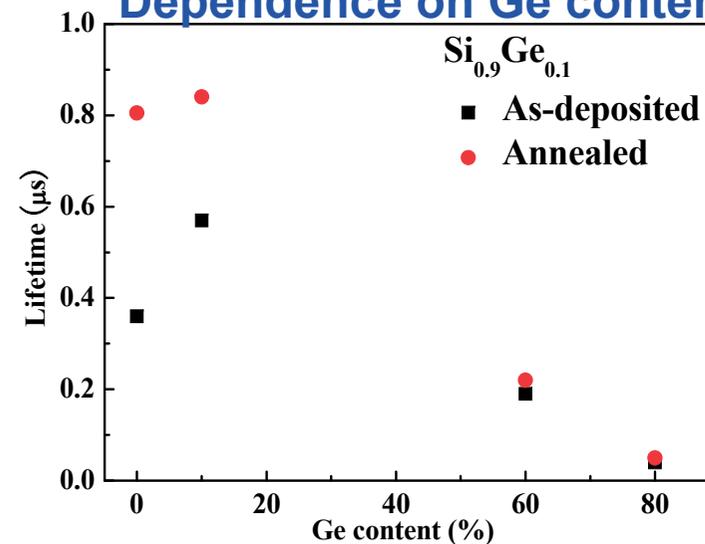


- ◆ Surface passivation with 0.01 molar quinhydrone in methanol solution
- ◆ Measure carrier lifetime with μ PCD

Post-annealed

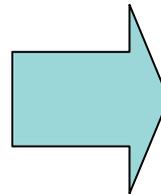
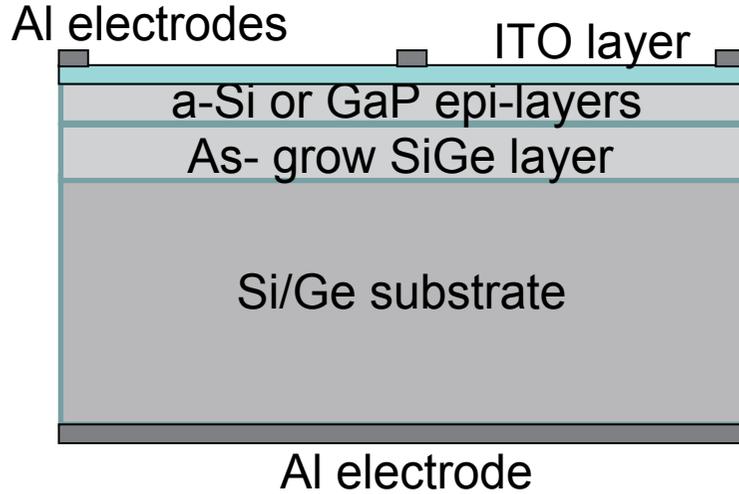


Dependence on Ge content

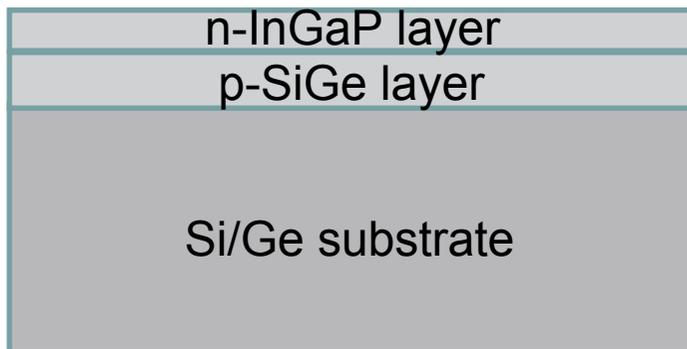


Heterojunction solar cells based on SiGe films

Test samples

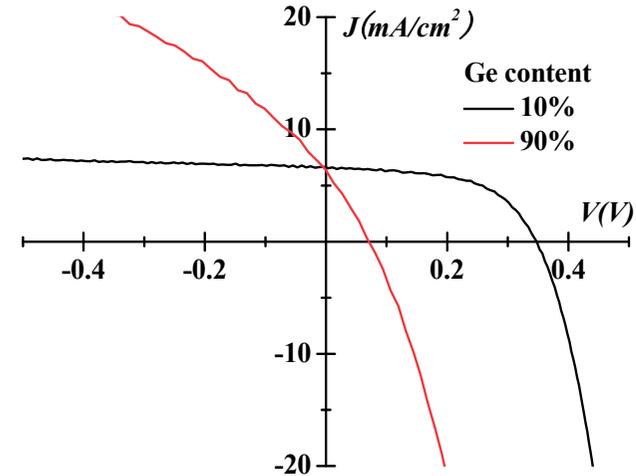


Final goal



ITO/a-Si/SiGe/Si(Ge) solar cells

I-V curves



IQE curves

